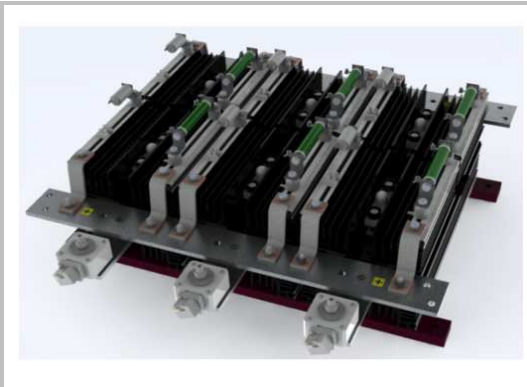


# SKS 845N B6HK 570 V16 SU



Thyristor/Diode Presspack stack

Electrical Characteristics						
Symbol	Conditions		min	typ	max	Unit
Electrical Data						
$I_D$	Maximum DC current	$T_{AMBIENT} = 45^\circ\text{C}$ ; No overload		845		A
$V_{AC}$	Maximum AC voltage (+/-10%)			500		$V_{AC}$
$V_{BUS}$	DC Bus voltage			670		$V_{DC}$
$P_{TOTAL}$	Maximum stack power			565		kW
$P_{LOSS}$	Stack power loss ( $T_{AMBIENT} = 45^\circ\text{C}$ )					W

Environmental Data						
Symbol	Conditions		min	typ	max	Unit
Mechanical Data						
Drawing	SEMIKRON document number.revision.version			11110416.01.B		-
Weight	Approximate total weight			106.0		kg
Altitude	Installation altitude without derating				1 000	m
Protection	IEC 60529			IP00		-
Pollution degree	EN 50178			2		-

## SEMISTACK® CLASSICS - B6HK

Three phase half-controlled rectifier

### Preliminary Data

Ordering No. 08800498  
Description SKS 845N B6HK 570 V16 SU

### Features

- Non-isolated power stacks
- SKN 1500/16 / SKT 760/16
- Heatsink U3/515
- Natural cooling
- RC circuit included
- Fuses with microswitches

### Typical Applications

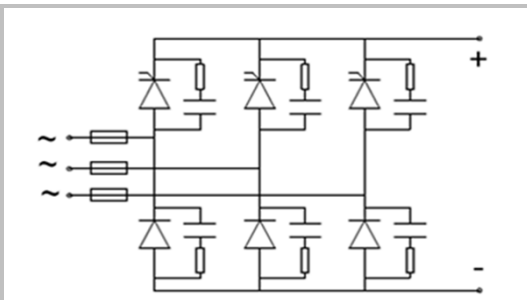
- Soft charge
- Industrial heating

### Remarks

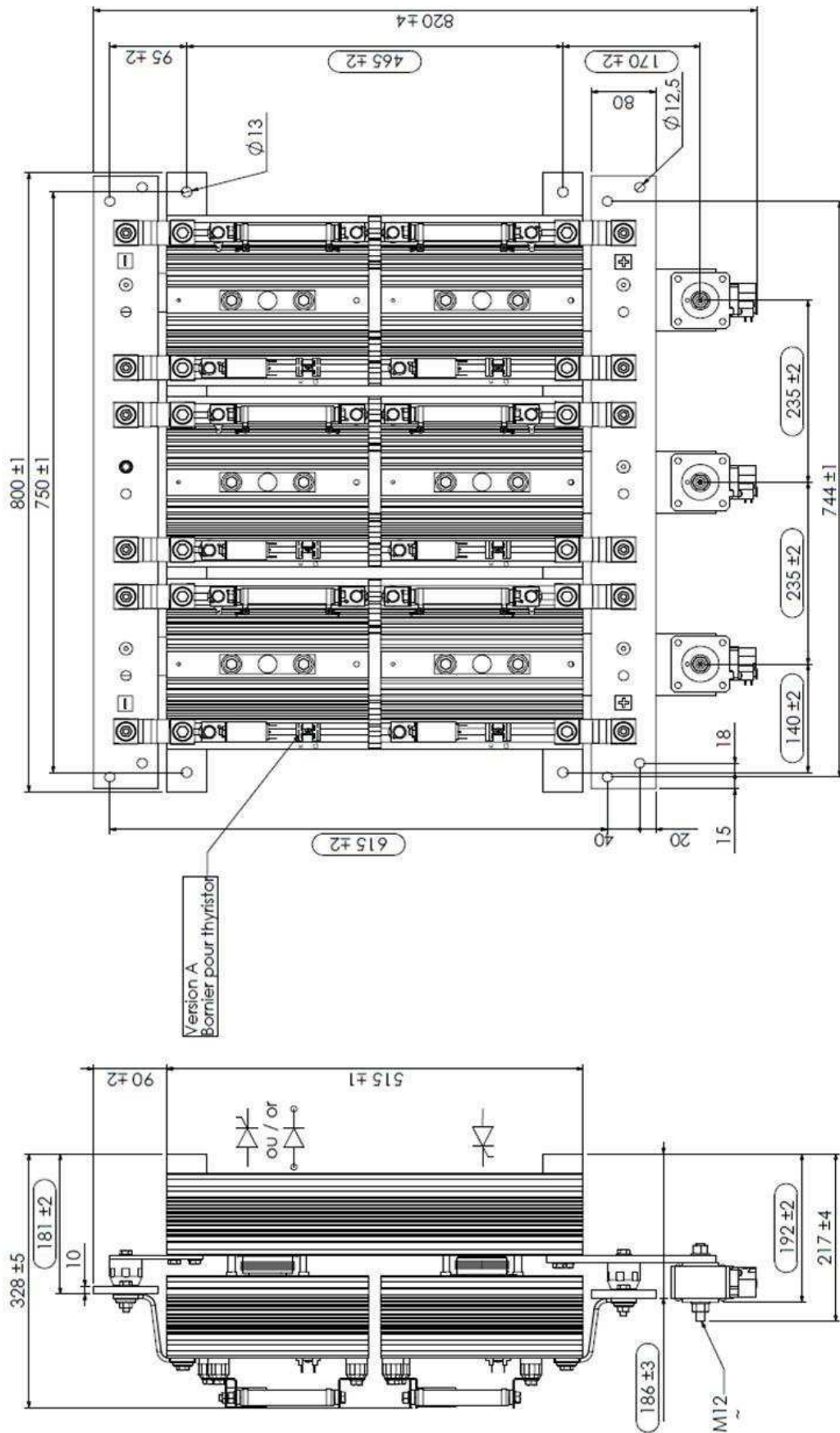
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Stack Protection						
Symbol	Conditions		min	typ	max	Unit
RC Circuit						
Type	RC in parallel with each electrical switch			-		-
R	Resistance (80W)			33		Ohm
C				0.47		$\mu\text{F}$

Fuses						
Symbol	Conditions		min	typ	max	Unit
Size	1 fuse per phase, with microswitches			33		-
$I_{N\text{RMS}}$	Caliber			1 250		A
$U_N$	Nominal voltage (IEC)			690		V
$I^2t$	Total at $U_N$ at room temperature (approx. 20...25°C)				1 942.5	$\text{kA}^2\text{s}$



B6HK



Dimensions

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